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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE  
ATTY. DOCKET NO. 50587-11 (RAB:rld)

In re Patent Application of Roger Maitland, et al

Serial No. 10/762,364

Group Art Unit: 2131

Filed: January 23, 2004

Examiner:



For: METHODS AND APPARATUS FOR PARALLEL IMPLEMENTATIONS OF TABLE LOOK-UPS AND CIPHERING

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

This Information Disclosure Statement is being filed in the manner prescribed by 37 CFR 1.97(b) - (d) to satisfy the duty under 37 CFR 1.56 to disclose to the Office information, known to individuals associated with the filing and prosecution of the subject application, which is material to the examination of the application.

In accordance with 37 CFR 1.97(g) and (h), this statement is not to be construed as a representation that a search has been made or an admission that the information cited herein is, or is considered to be, material to patentability as defined in 37 CFR 1.56(b).

This Information Disclosure Statement is being filed within three months of the filing date of a national application; within three months of the date of entry of the national stage as set forth in 37 CFR 1.491 in an international application; or before the mailing date of a first official action on the merits and therefore applicant respectfully requests consideration under 37 CFR 1.97(b).

I hereby certify that no item of information in the Information Disclosure Statement filed herewith was cited in a communication from a foreign patent office in a counterpart foreign application or, to my knowledge after making reasonable inquiry, was known to any individual designated in 37 CFR 1.56(c) more than three months prior to the filing of this Information

Disclosure Statement.

In compliance with 37 CFR 1.98(a)(2), also enclosed is a legible copy of:

- i) each foreign patent;
- ii) each publication or that portion which caused it to be listed; and
- iii) all other information or that portion which caused it to be listed, excluding any copies of a United States patent application.

In compliance with 37 CFR 1.98(a)(1), a list of all patents, publications, applications or other information submitted for consideration by the Office is hereby provided by way of the attached Form PTO-1449.

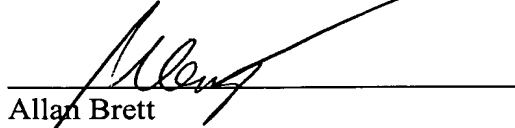
It is respectfully requested that the information be expressly considered by the Examiner and that the references be made of record and appear among the "References Cited" on any patent to issue therefrom.

The Patent Office is hereby authorized to charge any deficiency, or credit any overpayment in fees to Deposit Account Number 19-2550.

Respectfully submitted,

ROGER MAITLAND, ET AL


Dated: November 4, 2004



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Encls.:      Form PTO-1449  
              All references listed on Form PTO-1449  
              Acknowledgement Card

Form PTO-1449 (Modified)		Atty. Docket No. 50587-11	Serial No. 10/762,364
<b>LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT</b> (Use several sheets if necessary)		Applicant Roger Maitland, et al	
		Filing Date January 23, 2004	Group 2131

**REFERENCE DESIGNATION U.S. PATENT DOCUMENTS**

EXAM. INIT.		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FIL. DATE IF APPROPRIATE
	AA	6,223,320	Apr. 24, 2001	Dubey et al.	714	757	

**FOREIGN PATENT DOCUMENTS**

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION	
							YES	NO

**OTHER ART (including Author, Title, Date, Pertinent Pages, Etc.)**

	AB		<a href="http://www.simdtech.org/altivec">http://www.simdtech.org/altivec</a>  SIMD tech; ALTIVEC TECHNOLOGY, copyright© 2003 SIMD.
	AC		<a href="http://www.freescale.com/webapp/sps/site/overview.jsp?nodeId=018rH3bTdGmKqW5Nf2">http://www.freescale.com/webapp/sps/site/overview.jsp?nodeId=018rH3bTdGmKqW5Nf2</a>  freescale semiconductor; ALTIVEC™, 10/6/2004, pg 1-3.
	AD		Freescale Semiconductor, Inc.; ISN'T IT TIME YOU GOT FASTER, QUICKER?, AltiVec™ Technology At-a-Glance.
	AE		Joshi, Sanjay M., et al.; A NEW PARALLEL ALGORITHM FOR CRC GENERATION; IEEE, 2000, pp 1764-1768.
	AF		Williams, Ross N.; A PAINLESS GUIDE TO CRC ERROR DETECTION ALGORITHMS, Rocksoft™ Pty Ltd., August 19, 1993.

<b>EXAMINER</b>	<b>DATE CONSIDERED</b>
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EXAMINER:

Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.